TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ( $\pi$ -MOSVII)

# TK8A50D

## **Switching Regulator Applications**

Low drain-source ON-resistance: RDS (ON) =  $0.7 \Omega$  (typ.)

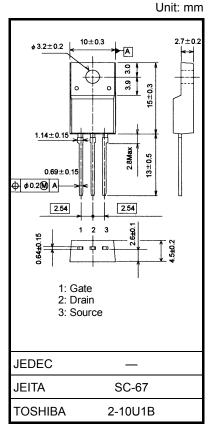
• High forward transfer admittance:  $|Y_{fs}| = 4.0 \text{ S (typ.)}$ 

• Low leakage current:  $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 500 \text{ V)}$ 

• Enhancement mode:  $V_{th} = 2.0 \text{ to } 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$ 

### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	500	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	8		
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	32	Α	
Drain power dissipati	on (Tc = 25°C)	PD	40	W	
Single pulse avalance	ne energy (Note 2)	E <sub>AS</sub>	165	mJ	
Avalanche current		I <sub>AR</sub>	8	Α	
Repetitive avalanche	energy (Note 3)	E <sub>AR</sub>	4.0	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

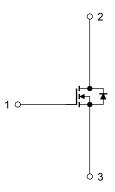
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.125	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = 90~V,~T_{ch} = 25^{\circ}C$  (initial), L = 4.4 mH, R<sub>G</sub> = 25  $\Omega,~I_{AR} = 8~A$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



# Electrical Characteristics (Ta = 25°C)

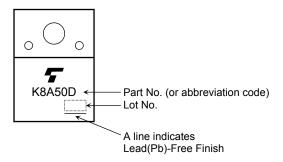
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±1	μА
Drain cut-off current		I <sub>DSS</sub>	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	_	_	10	μА
Drain-source breakdown voltage		V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	500	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON-	-resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4 A	_	0.7	0.85	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 4 A	1.0	4.0	_	S
Input capacitance		C <sub>iss</sub>		_	800	_	pF
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	4	_	
Output capacitance		C <sub>oss</sub>			100	_	
Switching time	Rise time	t <sub>r</sub>	$\begin{array}{c c} 10 \text{ V} & \text{ID} = 4 \text{ A} & \text{Vout} \\ \hline \text{VGS} & \text{OV} & \text{ID} = 4 \text{ A} & \text{Vout} \\ \hline \text{50 } \Omega & \text{SRL} = \\ \hline \text{50 } \Omega & \text{VDD} \approx 200 \text{ V} \\ \\ \hline \text{Duty} \leq 1\%, \ t_W = 10  \mu\text{S} \\ \end{array}$	_	20	_	
	Turn-on time	t <sub>on</sub>		_	40	_	20
	Fall time	t <sub>f</sub>			12	_	ns
	Turn-off time	t <sub>off</sub>		_	60	_	
Total gate charge		Qg		_	16	_	
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	_	10	_	nC
Gate-drain charge		Q <sub>gd</sub>		_	6	_	

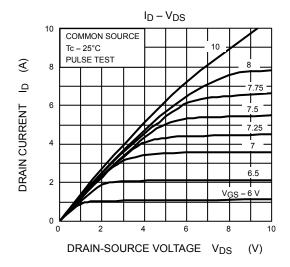
# Source-Drain Ratings and Characteristics (Ta = 25°C)

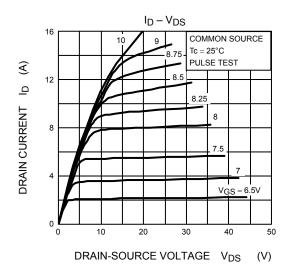
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	8	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	32	Α
Forward voltage (diode)	$V_{DSF}$	I <sub>DR</sub> = 8 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 8 A, V <sub>GS</sub> = 0 V,	_	1200	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs		10	_	μС

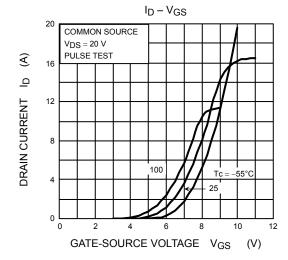
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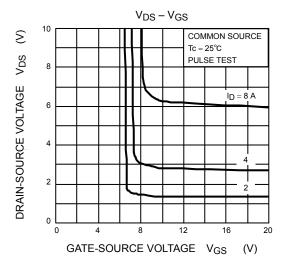
# Marking

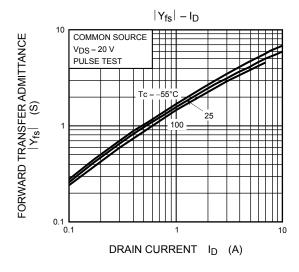


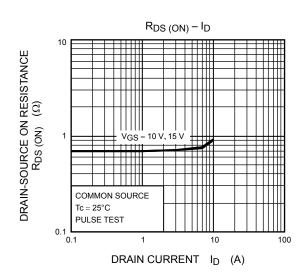




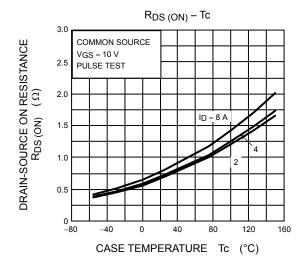


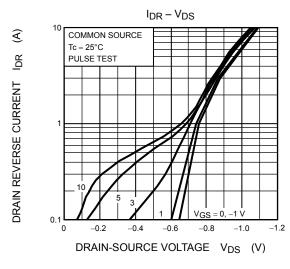


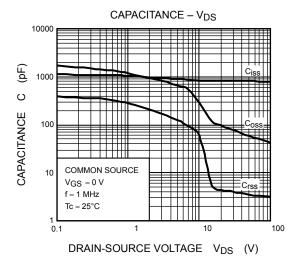


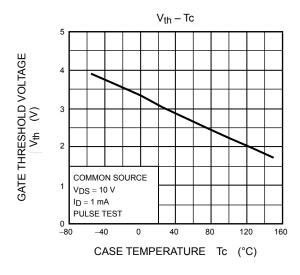


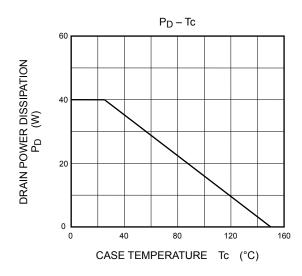
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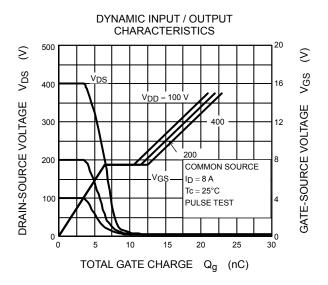




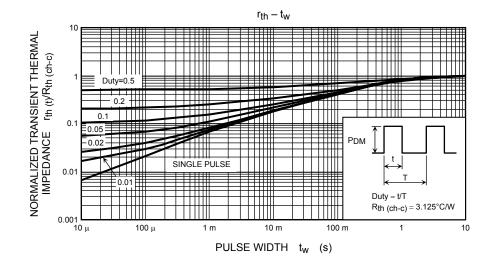


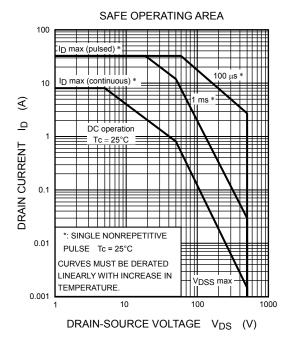


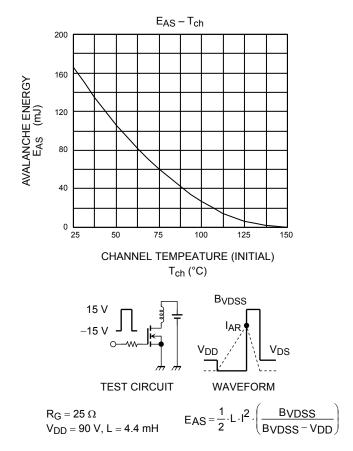




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